

COURSE OFFERING

Advanced Lithography THE 14/10/7NM NODES



Understand the key lithographic challenges required for 3D CMOS fabrication.

duration:

One Day

course brief:

This one-day course describes the current state-of-the-art as well as the latest advances in lithography for the 14/10/7nm nodes & beyond.



instructor:

Moshe Preil

For further information contact: 512-576-6404

© 2018 Threshold Systems.
All rights reserved.



course overview:

This course provides a broad, deep treatment of lithography which is the key enabling technology in CMOS IC fabrication. It covers all lithographic technology elements, from basic concepts to leading-edge technology and applications issues for today's most advanced CMOS ICs. The course explains all of the advances enabling 10nm CMOS and beyond, including leading-edge equipment and process evolution, double patterning technologies, computational lithography, Resolution Enhancement Technology (RET), design for manufacturability (DSM) and Extreme Ultra-Violet (EUV) lithography. It also will present a lithography road map describing next-generation lithography technologies.

appropriate for:

This course is appropriate for professional development of process engineers, applications engineers, device engineers, design engineers, technical marketing engineers and managers as well as process equipment engineers and scientists who wish to improve their understanding of modern lithography.

course outline:

Overview of enabling lithographic elements for the 14/10/7nm nodes:

- Review of key process and equipment concepts
- Deep UV chemically amplified resist technology and applications issues
- Process window latitude trade-offs, line edge roughness (LER), contrast, substrate reflectivity control, etch resistance, resist pattern collapse, process variation

Resolution Enhancement Technologies (RET):

- 193nm immersion (193i) lithography equipment performance status
- Sub-wavelength lithography gap & lithography for 14/10/7nm
- RET: customized illumination, optical proximity correction (OPC), sub-resolution assist features (SRAFs), phase shift masks (PSM), & photoresist feature "shrink" techniques
- Design for manufacturability (DFM) techniques to control variation
- Enabling technologies for 10/7nm CMOS
- Computational lithography technology (ILT, SMO, etc.)
- Double and triple patterning lithography (DPL) technologies

Next generation lithography status and road map:

- An extensive review of EUV (Extreme Ultra-Violet) 13.5nm wavelength lithography, challenges, issues and status
- Maskless electron beam direct write (EBDW) lithography
- Directed Self-Assembly (DSA) technology

This class is taught by a world-class lithographer and the information in the course is introductory in nature, profusely illustrated, and presented in a clear, technically current and easy-to-understand manner.

